



4/17/2012

**RELIABILITY MONITOR REPORT
FOR**

X3 0.6 μ m Silicon Gate CMOS (B6)

MAXIM Integrated Products

**120 San Gabriel Dr.
Sunnyvale, CA 94086**

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX7326ATG+

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 4341 QUANTITY: 32 FAILS: 0 FITS: 26.3

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2011 and 3/31/2012 .

Process Information:

Process Description: X3 0.6µm Silicon Gate CMOS (B6)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0549	MAX7326ATG+	135C	700 HRS	32	0	SYDBAQ001H
Total:						0	
FAILURE RATE:	MTTF (YRS): 4341		QUANTITY: 32	FAILS: 0	FITS: 26.3		